

Application/Control	No.
10/658.277	

Examiner
Chen-Wen Jiang

Applicant(s)/Patent under Reexamination VARNEY, BRIAN WILSON

Art Unit 3744

				ISSUE	CL	.AS	SIF	ICAT	ION					
		ORIGINAL						INT	ERNATIONAL	CLASSIFICATI	ON			
	LASS			CI	AIMED			ON-CLAIMED	N-CLAIMED					
	8	F	25	D	17	/00			1					
		F	17	С	9	/02			,					
CLASS	SUBCLA	R BLOCK)				,02			•					
62	50.2	611			F	25	j	1	/00			1		
									1			1		
									1			1		
									1			1		
									1			1		
- (Assistant Examiner) (Date)						EN 4	(Q)	4.6	Total Claims Allowed: 10					
(Assistant Examiner) (Date) (Legal Instruments Examiner) (Date)					Exami	ner)	> '	(Date))	O.G. Print Fi			
											1			

	Claims renumbered in the same order as presented by applicant							□СРА			☐ T.D.			☐ R.1.47					
Final	Original		Final	Original		Final	Original		Final	Original		Final	Original		Final	Original		Final	Original
	1]		31			61			91			121			151			181
	2			32			62			92			122			152			182
	3		10	33			63			93			123			153			183
	4			34			64			94			124			154			184
	5			35			65			95			125			155			185
	6			36			66			96			126			156			186
	7			37			67			97			127			157			187
	8			38			68			98			128			158			188
	ø			39		-	69			9			129			159			189
	10			40			70			100			130			160			190
	11			41			71			101			131			161			191
	12			42			72			102			132			162			192
	13			43			73			103			133			163			193
	14			44			74			104			134			164			194
1	15			45			75			105			135			165			195
	16			46			76		,	106			136			166			196
	17			47			77			107			137			167			197
	18			48			78			108			138			168			198
2	19	}		49			79	· .		109			139			169			199
3	20			50			80			110			140			170			200
4	21			51			81			111			141			171			201
8	22			52			82			112			142]		172			202
9	23	ļ		53			83			113			143]		173			203
5	24			54			84			114			144			174			204
6	25			55			85			115			145			175			205
7	26]		56			86			116			146			176			206
	27]		57			87			117			147			177			207
	28			58			88			118			148			178			208
	29			59			89			119			149			179			209
L	30	<u> </u>		60			90			120			150			180			210